

MOSFETs Silicon N-channel MOS (U-MOSIX-H)

TPN1200APL

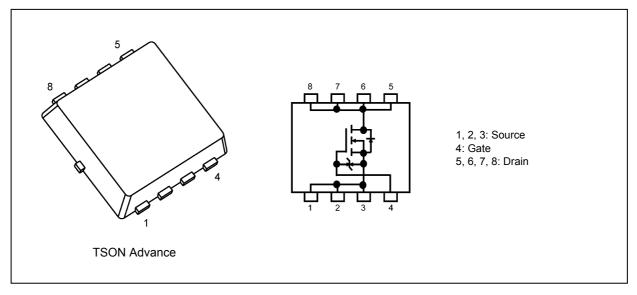
1. Applications

- · High-Efficiency DC-DC Converters
- Switching Voltage Regulators
- · Motor Drivers

2. Features

- (1) High-speed switching
- (2) Small gate charge: $Q_{SW} = 7.5 \text{ nC (typ.)}$
- (3) Small output charge: $Q_{oss} = 24 \text{ nC (typ.)}$
- (4) Low drain-source on-resistance: $R_{DS(ON)} = 9.8 \text{ m}\Omega$ (typ.) ($V_{GS} = 10 \text{ V}$)
- (5) Low leakage current: I_{DSS} = 10 μA (max) (V_{DS} = 100 V)
- (6) Enhancement mode: $V_{th} = 1.5 \text{ to } 2.5 \text{ V } (V_{DS} = 10 \text{ V}, I_D = 0.3 \text{ mA})$

3. Packaging and Internal Circuit





4. Absolute Maximum Ratings (Note) (Ta = 25 °C unless otherwise specified)

| Characteristics | | | Symbol | Rating | Unit |
|--------------------------------|--------------------------|--------------------|------------------|------------|------|
| Drain-source voltage | | | V_{DSS} | 100 | V |
| Gate-source voltage | | | V _{GSS} | ±20 | |
| Drain current (DC) | (T _c = 25 °C) | (Note 1) | I _D | 40 | Α |
| Drain current (DC) | (Silicon limit) | (Note 1), (Note 2) | | 66 | |
| Drain current (pulsed) | (t = 100 μs) | (Note 1) | I _{DP} | 160 | |
| Power dissipation | (T _c = 25 °C) | | P_{D} | 104 | W |
| Power dissipation | | (Note 3) | | 2.67 | |
| Power dissipation | | (Note 4) | | 0.63 | |
| Single-pulse avalanche energy | | (Note 5) | E _{AS} | 39 | mJ |
| Single-pulse avalanche current | | (Note 5) | I _{AS} | 32 | Α |
| Channel temperature | | | T _{ch} | 175 | °C |
| Storage temperature | | | T _{stg} | -55 to 175 | |

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

5. Thermal Characteristics

| Characteristics | Symbol | Max | Unit | | |
|---------------------------------------|--------------------------|----------|-----------------------|------|------|
| Channel-to-case thermal resistance | (T _c = 25 °C) | | R _{th(ch-c)} | 1.43 | °C/W |
| Channel-to-ambient thermal resistance | (T _a = 25 °C) | (Note 3) | R _{th(ch-a)} | 56 | |
| Channel-to-ambient thermal resistance | (T _a = 25 °C) | (Note 4) | R _{th(ch-a)} | 235 | |

Note 1: Ensure that the channel temperature does not exceed 175 °C.

Note 2: Limited by silicon chip capability.

Note 3: Device mounted on a glass-epoxy board (a), Figure 5.1

Note 4: Device mounted on a glass-epoxy board (b), Figure 5.2

Note 5: V_{DD} = 60 V, T_{ch} = 25 °C (initial), L = 42 μ H, I_{AS} = 32 A

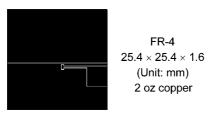
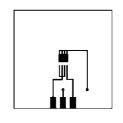


Fig. 5.1 Device Mounted on a Glass-Epoxy Board (a)



FR-4 $25.4 \times 25.4 \times 1.6$ (Unit: mm) 2 oz copper

Fig. 5.2 Device Mounted on a Glass-Epoxy Board (b)

Note: This transistor is sensitive to electrostatic discharge and should be handled with care.



6. Electrical Characteristics

6.1. Static Characteristics (T_a = 25 °C unless otherwise specified)

| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|----------------------|---|-----|------|------|------|
| Gate leakage current | I _{GSS} | $V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$ | _ | _ | ±10 | μΑ |
| Drain cut-off current | I _{DSS} | V _{DS} = 100 V, V _{GS} = 0 V | _ | _ | 10 | |
| Drain-source breakdown voltage | V _{(BR)DSS} | I _D = 10 mA, V _{GS} = 0 V | 100 | | | V |
| Drain-source breakdown voltage (Note 6) | V _{(BR)DSX} | $I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$ | 65 | | | |
| Gate threshold voltage | V_{th} | $V_{DS} = 10 \text{ V}, I_{D} = 0.3 \text{ mA}$ | 1.5 | _ | 2.5 | |
| Drain-source on-resistance | R _{DS(ON)} | V _{GS} = 4.5 V, I _D = 14 A | _ | 13.3 | 20 | mΩ |
| | | $V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$ | _ | 9.8 | 11.5 | |

Note 6: If a reverse bias is applied between gate and source, this device enters $V_{(BR)DSX}$ mode. Note that the drain-source breakdown voltage is lowered in this mode.

6.2. Dynamic Characteristics (T_a = 25 °C unless otherwise specified)

| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|--------------------------------|------------------|--|-----|------|------|------|
| Input capacitance | C _{iss} | V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz | _ | 1425 | 1855 | pF |
| Reverse transfer capacitance | C _{rss} | | _ | 15 | 50 | |
| Output capacitance | C _{oss} | | _ | 205 | _ | |
| Gate resistance | r _g | _ | _ | 2.1 | 3.2 | Ω |
| Switching time (rise time) | t _r | See Fig. 6.2.1 | _ | 6 | _ | ns |
| Switching time (turn-on time) | t _{on} | | _ | 19 | _ | |
| Switching time (fall time) | t _f | | _ | 6 | _ | |
| Switching time (turn-off time) | t _{off} | | _ | 34 | _ | |

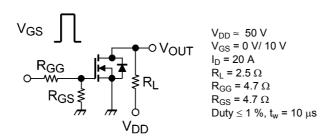


Fig. 6.2.1 Switching Time Test Circuit

6.3. Gate Charge Characteristics (T_a = 25 °C unless otherwise specified)

| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|-------------------------------------|------------------|---|-----|------|-----|------|
| Total gate charge (gate-source plus | Q_{g} | $V_{DD} \approx 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$ | _ | 24 | _ | nC |
| gate-drain) | | $V_{DD} \approx 50 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$ | | 12 | | |
| Gate-source charge 1 | Q _{gs1} | $V_{DD} \approx 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$ | | 5.6 | | |
| Gate-drain charge | Q_{gd} | | | 4.9 | _ | |
| Gate switch charge | Q_{SW} | | _ | 7.5 | _ | |
| Output charge | Q_{oss} | $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ | _ | 24 | _ | |



6.4. Source-Drain Characteristics (T_a = 25 °C unless otherwise specified)

| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|----------------------------------|---|-----|------|------|------|
| Reverse drain current (pulsed) (Note 7) | I _{DRP} (t = 100 μs) | _ | ı | ı | 160 | Α |
| Diode forward voltage | V_{DSF} | I _{DR} = 40 A, V _{GS} = 0 V | | | -1.2 | V |
| Reverse recovery time | | I_{DR} = 10 A, V_{GS} = 0 V, | _ | 41 | _ | ns |
| Reverse recovery charge | Q _{rr} | -dI _{DR} /dt = 100 A/μs | _ | 47 | _ | nC |

Note 7: Ensure that the channel temperature does not exceed 175 °C.

7. Marking

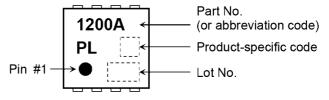


Fig. 7.1 Marking



8. Characteristics Curves (Note)

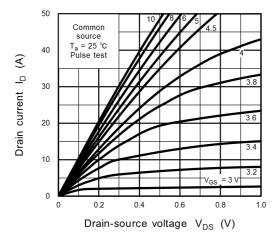
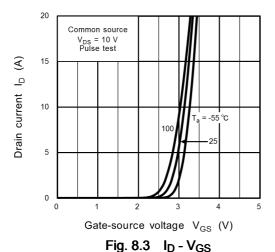


Fig. 8.1 I_D - V_{DS}



1 ig. 0.0 ip vgs

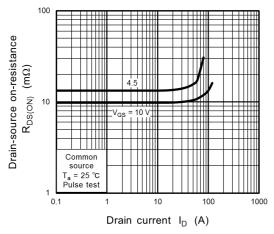


Fig. 8.5 R_{DS(ON)} - I_D

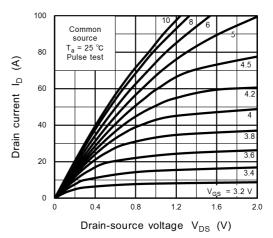


Fig. 8.2 I_D - V_{DS}

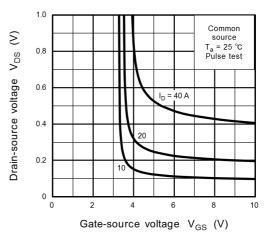


Fig. 8.4 V_{DS} - V_{GS}

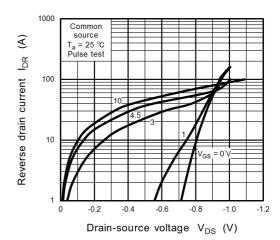


Fig. 8.6 IDR - VDS



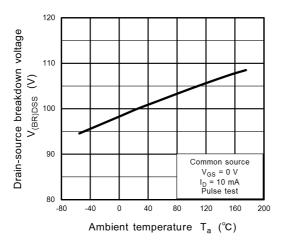


Fig. 8.7 V_{(BR)DSS} - T_a

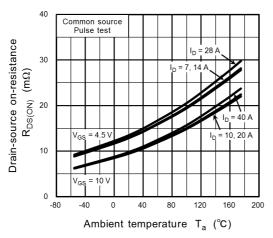


Fig. 8.9 R_{DS(ON)} - T_a

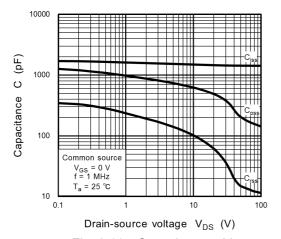


Fig. 8.11 Capacitance - V_{DS}

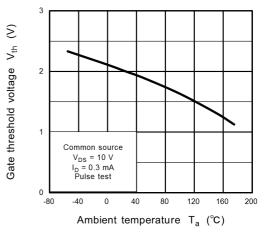


Fig. 8.8 V_{th} - T_a

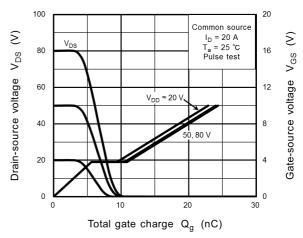


Fig. 8.10 Dynamic Input/Output Characteristics

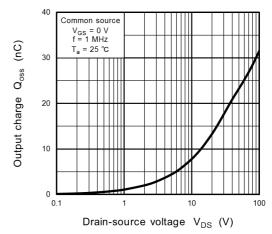


Fig. 8.12 Qoss - VDS



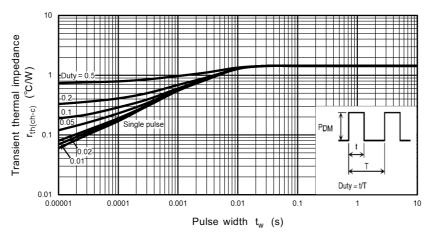


Fig. 8.13 r_{th} - t_w (Guaranteed Maximum)

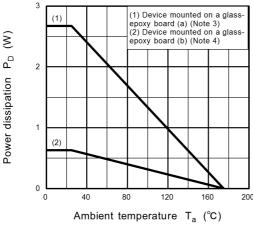


Fig. 8.14 P_D - T_a (Guaranteed Maximum)

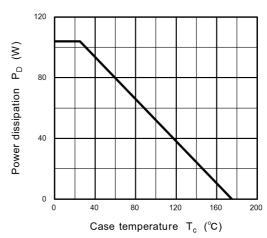


Fig. 8.15 P_D - T_c (Guaranteed Maximum)

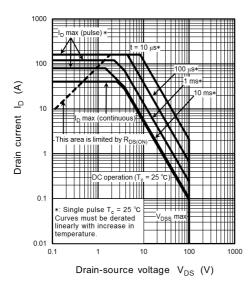


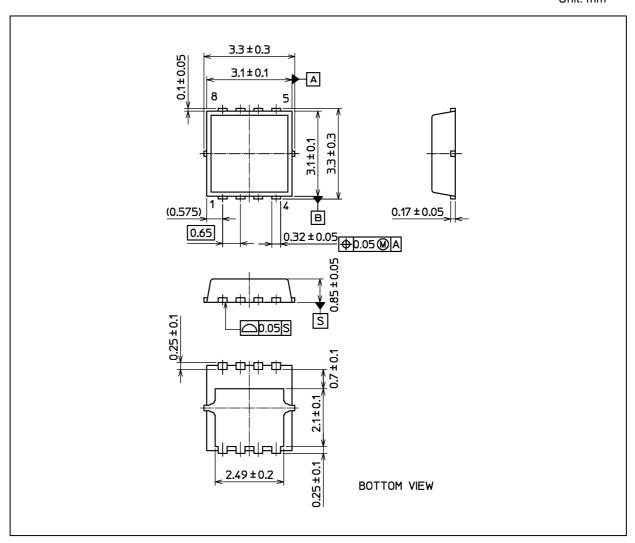
Fig. 8.16 Safe Operating Area (Guaranteed Maximum)

Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



Package Dimensions

Unit: mm



Weight: 0.029 g (typ.)

| Package Name(s) | |
|------------------------|--|
| TOSHIBA: 2-3X1S | |
| Nickname: TSON Advance | |



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